Notice of References Cited Application/Control No. 09/763,210 Examiner Dave T Nguyen Applicant(s)/Patent Under Reexamination SHIH ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,040,295	03-2000	Rolland et al.	514/44
	В	US-6,066,624	05-2000	Woo et al.	514/44
	С	US-6,451,256	09-2002	Sene, Claude	422/40
	D	US-2003/0211598	11-2003	Engler et al.	435/320.1
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 98/02522	01-1998	WIPO	Sene	
	0					·
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.